



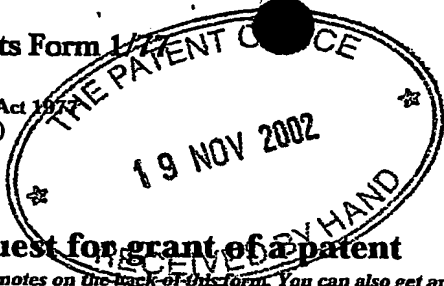
10/532345

**INVESTOR IN PEOPLE**

**SUBMITTED OR TRANSMITTED IN  
COMPLIANCE WITH RULE 17.1(a) OR (b)**

WIPO PCT

An Executive Agency of the Department of Trade and Industry



1/77

# Request for grant of a patent

(See the notes on the back of this form. You can also get an explanatory leaflet from the Patent Office to help you fill in this form)

The Patent Office

Cardiff Road  
Newport  
South Wales  
NP9 1RH

## 1. Your reference

RSJ07644GB

## 2. Patent application number

(The Patent Office will fill in this part)

0226996.7

19 NOV 2002

## 3. Full name, address and postcode of the or of each applicant (underline all surnames)

Oxford Instruments Superconductivity  
Limited  
Old Station Way, Eynsham  
Witney, Oxford,  
OX8 1TL, Great Britain

Patents ADP number (if you know it)

If the applicant is a corporate body, give the country/state of its incorporation

Great Britain

08189367001

## 4. Title of the invention

SAMPLE INSPECTION APPARATUS

## 5. Name of your agent (if you have one)

Gill Jennings & Every

"Address for service" in the United Kingdom to which all correspondence should be sent (including the postcode)

Broadgate House  
7 Eldon Street  
London  
EC2M 7LH

Patents ADP number (if you know it)

745002

## 6. If you are declaring priority from one or more earlier patent applications, give the country and the date of filing of the or of each of these earlier applications and (if you know it) the or each application number

Country

Priority application number  
(if you know it)

Date of filing  
(day / month / year)

## 7. If this application is divided or otherwise derived from an earlier UK application, give the number and the filing date of the earlier application

Number of earlier application

Date of filing  
(day / month / year)

## 8. Is a statement of inventorship and of right to grant of a patent required in support of this request? (Answer 'Yes' if:

YES

- a) any applicant named in part 3 is not an inventor, or
  - b) there is an inventor who is not named as an applicant, or
  - c) any named applicant is a corporate body.
- See note (d))

# Patents Form 1/77

9. Enter the number of sheets for any of the following items you are filing with this form. Do not count copies of the same document

Continuation sheets of this form

Description

6

Claim(s)

2

Abstract

Drawing(s)

4

+4

10. If you are also filing any of the following, state how many against each item.

Priority documents

Translations of priority documents

Statement of inventorship and right to grant of a patent (Patents Form 7/77)

Request for preliminary examination and search (Patents Form 9/77)

Request for substantive examination (Patents Form 10/77)

Any other documents (please specify)

NO

11. For the applicant  
Gill Jennings & Every

I/We request the grant of a patent on the basis of this application.

Signature



Date

19 November 2002

12. Name and daytime telephone number of person to contact in the United Kingdom

R.E. Skone James

020 7377 1377

## Warning

After an application for a patent has been filed, the Comptroller of the Patent Office will consider whether publication or communication of the invention should be prohibited or restricted under Section 22 of the Patents Act 1977. You will be informed if it is necessary to prohibit or restrict your invention in this way. Furthermore, if you live in the United Kingdom, Section 23 of the Patents Act 1977 stops you from applying for a patent abroad without first getting written permission from the Patent Office unless an application has been filed at least 6 weeks beforehand in the United Kingdom for a patent for the same invention and either no direction prohibiting publication or communication has been given, or any such direction has been revoked.

## Notes

- If you need help to fill in this form or you have any questions, please contact the Patent Office on 0645 500505.
- Write your answers in capital letters using black ink or you may type them.
- If there is not enough space for all the relevant details on any part of this form, please continue on a separate sheet of paper and write "see continuation sheet" in the relevant part(s). Any continuation sheet should be attached to this form.
- If you have answered 'Yes' Patents Form 7/77 will need to be filed.
- Once you have filled in the form you must remember to sign and date it.
- For details of the fee and ways to pay please contact the Patent Office.

SAMPLE INSPECTION APPARATUS

The invention relates to sample inspection apparatus and in particular to nuclear magnetic resonance (NMR) inspection apparatus.

NMR has been developed over many years to enable chemical information about samples such as their structure to be obtained. This is carried out using NMR spectroscopy. The NMR process involves the generation of a high strength, uniform magnetic field within a working volume. The sample is located in the working volume and then subjected to RF irradiation causing the spins of certain nuclei to precess. On removing the RF irradiation, the spins return to their rest state and their precession frequency can be monitored thus giving an indication of structural information and the like.

In many analytical situations, other information about samples is often needed as well thus requiring additional experimental equipment to be provided. An example is Fourier Transform Ion Cyclotron Resonance Mass Spectroscopy (FTICR or FTMS). In FTICR, ions from the sample under investigation are exposed to a high strength, substantially uniform magnetic field while being rotated at high speed (experiencing cyclotron excitation) and subjected to RF irradiation.

Typically, chemical samples of very small volume are analysed, typically in the order of femtomoles.

A number of problems arise in these circumstances. Firstly, each experiment requires a high strength magnet and these are large, bulky and very expensive. In addition, problems arise when attempting to analyse the same sample in more than one way since there are risks of contamination and an inability to carry out the tests simultaneously.

In accordance with the present invention, we provide sample inspection apparatus comprising a magnet

assembly located in a cryostat and surrounding a bore at room temperature so as to define one or more working regions in the bore; a first, NMR probe which can be inserted in the bore to bring a sample into the or one of the working regions, the magnetic field in that working region having a homogeneity or profile suitable for performing a NMR experiment; and a second probe which can be inserted in the bore to bring a sample into the or another working region, the magnetic field in that working region having a homogeneity or profile suitable for performing a different experiment on the sample.

We have realised that there are significant synergies between NMR apparatus on the one hand and certain other experimental apparatus, particularly FTICR, on the other hand. Thus, both require a high strength, substantially uniform magnetic field and thus both typically need a cryostat in order to cool the windings of a magnet to low temperature to achieve superconductivity. This enables the high strength magnetic field to be generated cost effectively. Each type of apparatus uses a probe within which the sample is located in use, the probe being inserted into a room temperature bore of the cryostat.

In a first example, the magnet assembly defines two separate magnets spaced apart along the bore, each generating a uniform magnetic field within its own working region, one suitable for the NMR experiment and the other suitable for the different experiment. The advantage of this arrangement is that a single cryostat can be utilised.

In this case, the two probes can be arranged simultaneously in the bore so that both experiments can be carried out simultaneously. As will be explained in more detail below, this allows the same sample to be analysed in two different ways substantially simultaneously and avoids problems of time delay between carrying out the two experiments, contamination etc.

In more preferred arrangements, the magnet assembly comprises a single magnet and this could be wound in order to generate two separate working regions of substantially uniform magnetic field but typically will  
5 generate a single working region of substantially uniform magnetic field in the bore.

In this latter case, the probes can be inserted into the bore in turn or more preferably can be inserted from opposite ends of the bore with one probe being arranged  
10 to bring its sample into the working region followed by the other.

In a particularly preferred arrangement, the probes are constructed so that both can bring their respective samples into the same working region simultaneously.  
15 This could be achieved, for example, by making the ends of the two probes male and female so that they will interengage.

Typically, the magnet assembly will be actively shielded to reduce the fringe field strength.

20 Although the "different experiment" is described herein as FTICR, other experiments are also possible, namely EPR (electron paramagnetic resonance) or ESP (electron spin resonance).

Advantages of the invention include a reduced cost  
25 since only a single cryostat, and in most cases a single magnet, is required to obtain the same experimental data previously requiring two separate structures. Also the proximity or even commonality of the two working regions provides for increased sample throughput, reduced  
30 contamination, and improved confidence of data, for example when needing to process FTICR data and NMR data simultaneously particularly with respect to mass confirmation in conjunction with NMR. An example of this is the need to use NMR to obtain the 3D structure of a  
35 protein and FTICR to obtain peptide sequencing data.

Some examples of apparatus according to the present invention will now be described with reference to the accompanying drawings, in which:-

Figure 1 is a block diagram illustrating the primary components of an analytical instrument applicable to any of the examples shown in the following drawings;

Figure 2 is a longitudinal section through a first example of the sample inspection apparatus;

Figures 3A and 3B are longitudinal sections through a second example in two different conditions; and,

Figures 4A and 4B are a longitudinal section and a cross-section respectively through a third example of the apparatus.

The apparatus shown in Figure 1 comprises a conventional liquid chromatograph 1 to which a sample to be analysed is supplied. The chromatograph 1 separates out the component to be analysed which, as explained above, will be of very small volume, and this is fed to a flow splitter 2. The sample is then split with a proportion passing to NMR sample injection equipment 3 and the remaining portion to ICR mass spectrometer sample injection equipment 4. The sample from the equipment 4 is then supplied to an ICR mass spectrometer ultra high vacuum (UHV) cell 5 while the sample from the equipment 3 is passed to an NMR RF probe 6.

In operation, the cell 5 and the probe 6 will generate output signals which are captured and then processed, typically by a common microcomputer or other processor so that the results can be compared accurately and easily on the basis that the tests were carried out simultaneously on the same sample.

Figure 2 illustrates a first example of the sample inspection apparatus which can be used with the Figure 1 arrangement. The apparatus comprises a cryostat 10 of conventional form having a central liquid helium vessel 12 accessed via an access and service neck 14. This is surrounded by a gas cooled radiation shield 16 which in

turn is surrounded by a liquid nitrogen containing vessel 18. Finally, the outer wall 20 of the cryostat is separated from the liquid nitrogen vessel 18 by an evacuated chamber 22.

5       The cryostat surrounds a room temperature bore having a large diameter section 24 continuing into a narrower diameter section 26. An actively shielded magnet assembly 28 is located in the liquid helium vessel 12 and surrounds the bore 24,26. The magnet assembly is  
10 split into two sections, one surrounding each part of the bore 24,26 and each generating a substantially uniform field within a respective working region 30,32. Typical examples of the uniformity achieved in each region are  $\pm 100$ ppm within a 50mm diameter and 80mm length cylinder  
15 for the region 30 and  $\pm 10^{-8}$  within a 5mm diameter and 20mm length cylinder for the region 32.

In addition to the main, actively shielded magnet, additional shims etc (not shown) will be provided either in the cryostat or in the room temperature bore 24,26 as  
20 required. This will be well understood by a person of ordinary skill in the art and so will not be described further in detail.

Removably inserted into the bore 26 is a NMR RF probe 6 which also contains shim coils and sample  
25 injection equipment. Into the bore 24 is inserted a UHV ICR cell and sample injection equipment 5. The cell 5 and probe 6 will be connected to the other equipment as shown in Figure 1.

In operation, magnetic fields of the desired  
30 strength and uniformity can be produced simultaneously in the working volumes 30,32 so that the FTICR and NMR experiments can be carried out on the samples simultaneously.

Figures 3A and 3B illustrate a second example. In  
35 this example, the basic construction of the cryostat is the same as in the Figure 2 example and will not be described further. The difference between the two



examples is that a single room temperature bore 34 having a substantially constant cross-section is provided and a single working region 36 having a substantially uniform magnetic field is generated by the magnet assembly 28.

5 The ICR cell probe 5 and the NMR probe 6 are simultaneously located in the bore 34 but only one can be brought into alignment with the working region 36 at any one time. In Figure 3A, the FTICR cell probe 5 has been brought to bring its sample region into the working  
10 region 36 while in Figure 3B the NMR probe 6 has been pushed into the bore sufficiently to bring its sample region into alignment with the working region.

Figures 4A and 4B illustrate a further example similar to the Figure 3 example in which a single working  
15 region 40 is produced with a substantially uniform magnetic field by the magnet 28. The difference between this example and the previous example is that the probe 5 defines a central, blind bore 42 into which the NMR RF probe 6 can be inserted. This enables the sample region  
20 44 of the probe 6 and the experimental volume 46 of the probe 5 to be made axially coincident.

CLAIMS

1. Sample inspection apparatus comprising a magnet assembly located in a cryostat and surrounding a bore at room temperature so as to define one or more working regions in the bore; a first, NMR probe which can be inserted in the bore to bring a sample into the or one of the working regions, the magnetic field in that working region having a homogeneity or profile suitable for performing a NMR experiment; and a second probe which can be inserted in the bore to bring a sample into the or another working region, the magnetic field in that working region having a homogeneity or profile suitable for performing a different experiment on the sample.
2. Apparatus according to claim 1, wherein the probes are insertable into opposite ends of the bore.
3. Apparatus according to claim 1 or claim 2, wherein two working regions are defined in the bore, the working regions being laterally spaced apart along the bore.
4. Apparatus according to claim 3, wherein the magnet assembly comprises a single magnet.
5. Apparatus according to claim 3 or claim 4, wherein the magnet assembly is controllable to generate the required magnetic fields in each working region simultaneously.
6. Apparatus according to claim 1 or claim 2, wherein a single working region is provided, the probes being constructed so that both can bring their respective samples into the same working region simultaneously.
7. Apparatus according to claim 6, wherein the probes are constructed with male and female ends which interengage.
8. Apparatus according to any of claims 5 to 7, further comprising a system for supplying portions of a sample to each probe from a common source.
9. Apparatus according to claim 8, wherein the common source comprises a liquid chromatograph.
10. Apparatus according to claim 1 or claim 2, wherein a single working region is defined in the bore, each probe

being fully removable from the bore to allow the other probe to be inserted.

11. Apparatus according to any of the preceding claims, wherein the second probe is suitable for use in ion  
5 cyclotron resonance mass spectroscopy.

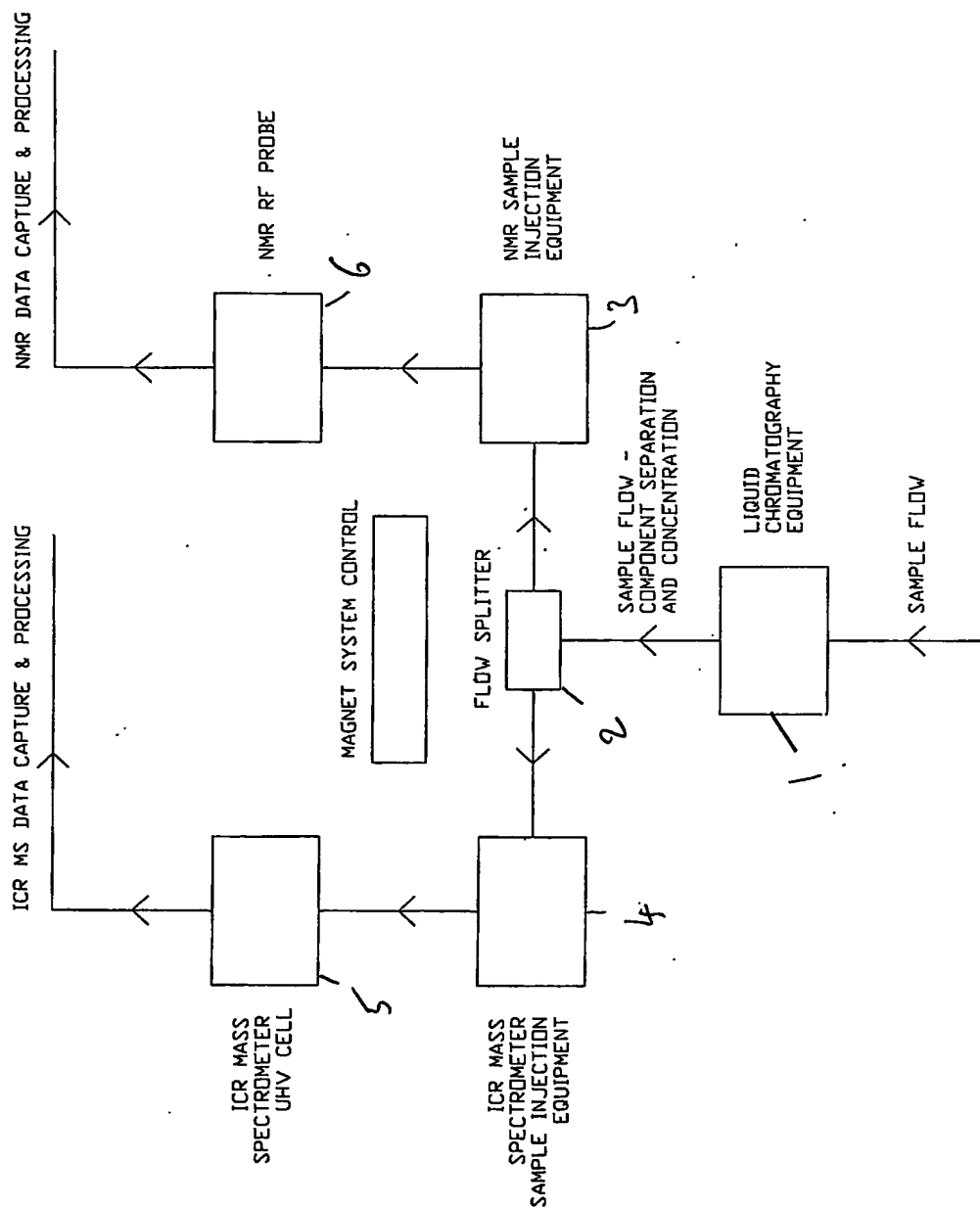


FIG-1

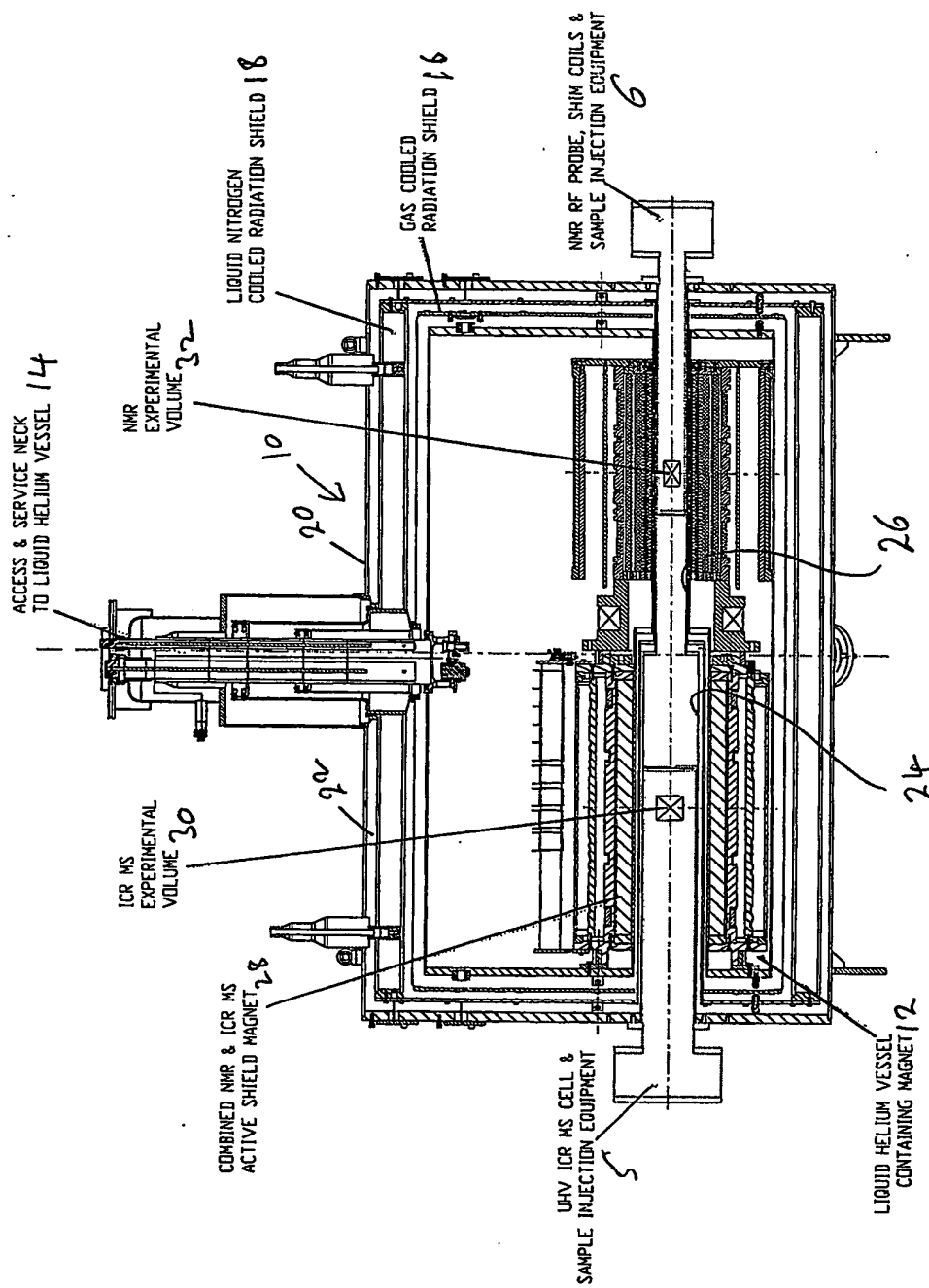
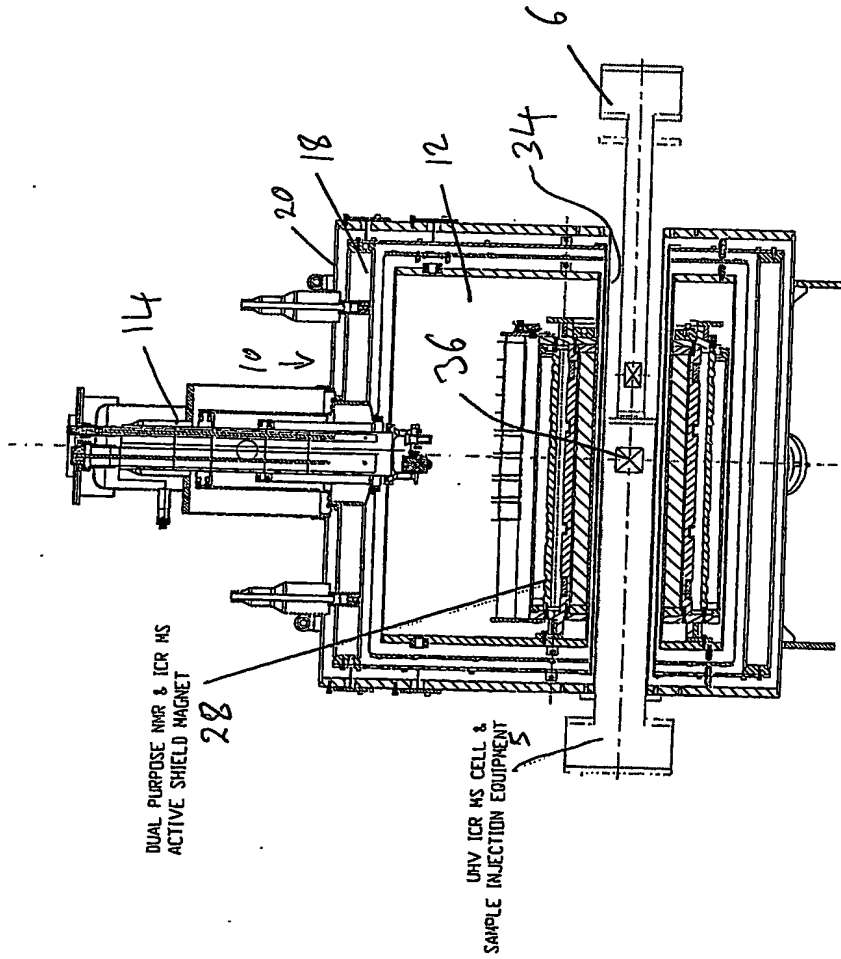
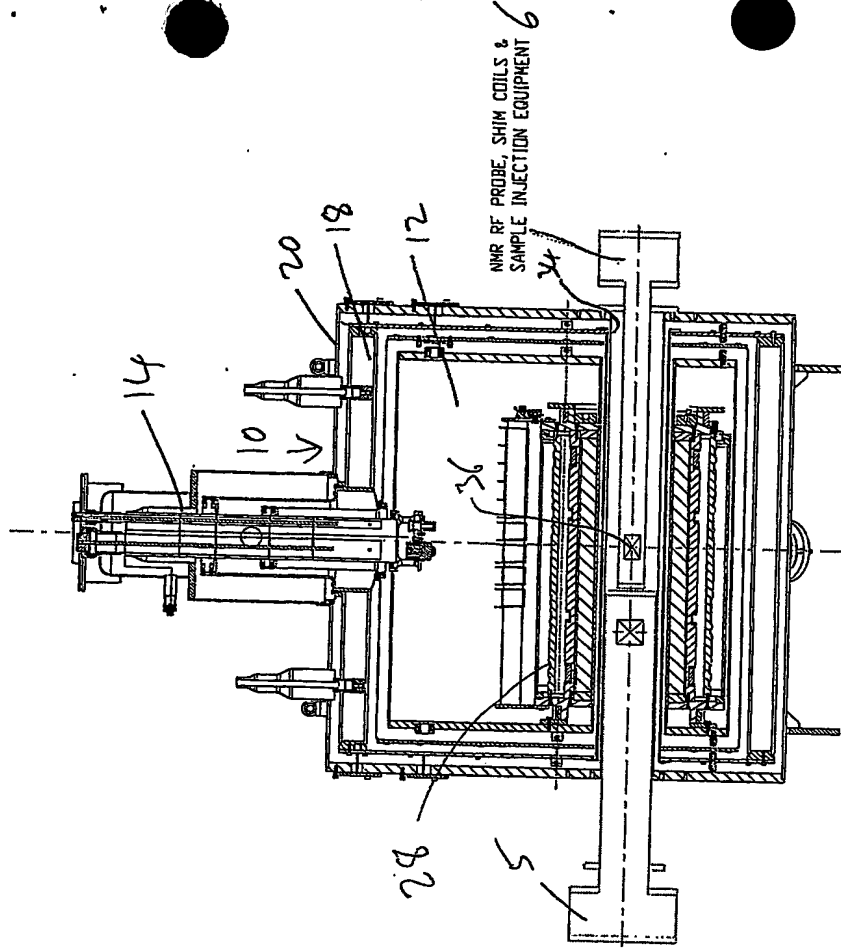


FIG 2



CONFIGURATION 1 - ICR MS MEASUREMENT

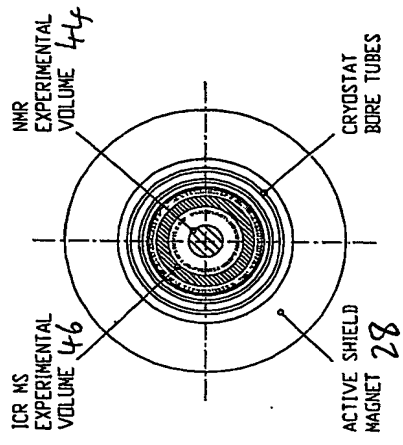
(A)



CONFIGURATION 2 - NMR MEASUREMENT

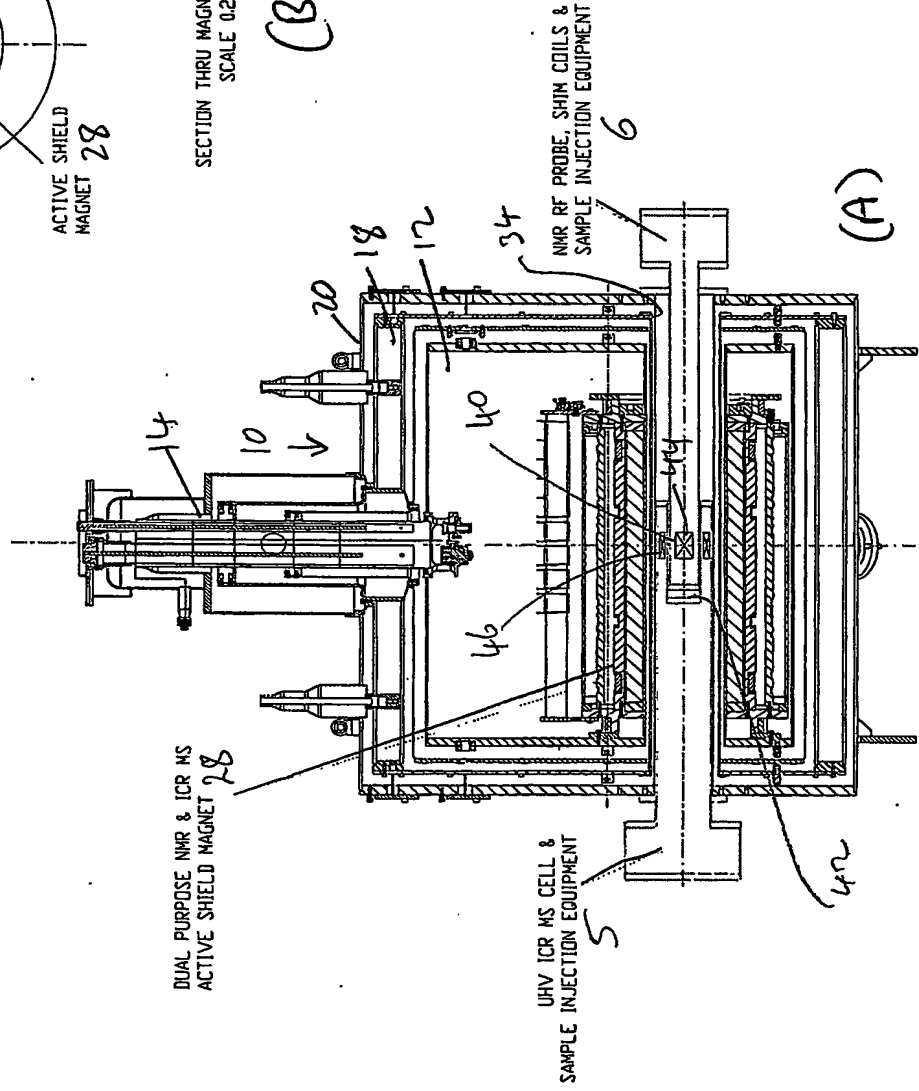
(B)

FIG 3



SECTION THRU MAGNET CENTRE  
SCALE 0.2

(B)



(A)

FIG 4

PCT Application

**GB0304987**





**This Page is Inserted by IFW Indexing and Scanning  
Operations and is not part of the Official Record**

**BEST AVAILABLE IMAGES**

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

☐ BLACK BORDERS

☐ IMAGE CUT OFF AT TOP, BOTTOM OR SIDES

☒ FADED TEXT OR DRAWING

☒ BLURRED OR ILLEGIBLE TEXT OR DRAWING

☐ SKEWED/SLANTED IMAGES

☐ COLOR OR BLACK AND WHITE PHOTOGRAPHS

☐ GRAY SCALE DOCUMENTS

☒ LINES OR MARKS ON ORIGINAL DOCUMENT

☐ REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY

☐ OTHER: \_\_\_\_\_

**IMAGES ARE BEST AVAILABLE COPY.**

**As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.**